



## **FQD4P40 / FQU4P40**

#### **400V P-Channel MOSFET**

#### **General Description**

These P-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for electronic lamp ballast based on complimentary half bridge.

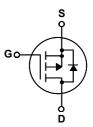
#### **Features**

- -2.7A, -400V,  $R_{DS(on)} = 3.1\Omega$  @V<sub>GS</sub> = -10 V
- Low gate charge (typical 18 nC)
- Low Crss (typical 11 pF)
- · Fast switching
- 100% avalanche tested
- · Improved dv/dt capability
- RoHS Compliant









## **Absolute Maximum Ratings** $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter		FQD4P40 / FQU4P40	Units
$V_{DSS}$	Drain-Source Voltage		-400	V
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°C) - Continuous (T <sub>C</sub> = 100°C)		-2.7	Α
			-1.71	А
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	-10.8	Α
V <sub>GSS</sub>	Gate-Source Voltage		± 30	V
E <sub>AS</sub>	Single Pulsed Avalanche Energy	(Note 2)	260	mJ
I <sub>AR</sub>	Avalanche Current	(Note 1)	-2.7	Α
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	5.0	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	-4.5	V/ns
P <sub>D</sub>	Power Dissipation (T <sub>A</sub> = 25°C) *		2.5	W
	Power Dissipation (T <sub>C</sub> = 25°C)		50	W
	- Derate above 25°C		0.4	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C
T <sub>L</sub>	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

#### **Thermal Characteristics**

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	R <sub>0JC</sub> Thermal Resistance, Junction-to-Case		2.5	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *		50	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		110	°C/W

<sup>\*</sup> When mounted on the minimum pad size recommended (PCB Mount)

Symbol	Parameter	Parameter Test Conditions		Тур	Max	Units
Off Cha	aracteristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	-400			V
ΔBV <sub>DSS</sub> / ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	$I_D$ = -250 μA, Referenced to 25°C		0.36		V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = -400 V, V <sub>GS</sub> = 0 V			-1	μΑ
		V <sub>DS</sub> = -320 V, T <sub>C</sub> = 125°C			-10	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = -30 V, V <sub>DS</sub> = 0 V			-100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	V <sub>GS</sub> = 30 V, V <sub>DS</sub> = 0 V			100	nA
On Cha	racteristics					
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250 μA	-3.0		-5.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = -10 V, I <sub>D</sub> = -1.35 A		2.44	3.1	Ω
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = -50 V, I <sub>D</sub> = -1.35 A (Note 4)		2.5		S
C <sub>oss</sub>	Output Capacitance Reverse Transfer Capacitance	$V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		80 11	105 15	pF pF
C <sub>rss</sub>	Reverse Transfer Capacitance			11	15	pF
Switchi	ing Characteristics					
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = -200 V, I <sub>D</sub> = -3.5 A,		13	35	ns
t <sub>r</sub>	Turn-On Rise Time	$R_G = 25 \Omega$		55	120	ns
t <sub>d(off)</sub>	Turn-Off Delay Time			35	80	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4, 5)		37	85	ns
Qg	Total Gate Charge	V <sub>DS</sub> = -320 V, I <sub>D</sub> = -3.5 A,		18	23	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = -10 V		3.8		nC
Q <sub>gd</sub>	Gate-Drain Charge	(Note 4, 5)		9.4		nC
Drain S	Source Diode Characteristics a	ad Maximum Datings				
I <sub>S</sub>	Maximum Continuous Drain-Source Did				-2.7	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward Current				-10.8	Α
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = -2.7 A			-5.0	V
		$V_{GS} = 0 \text{ V, } I_{S} = -3.5 \text{ A,}$		260		no
t <sub>rr</sub>	Reverse Recovery Time	VGS - U V, IS3.3 A,		200		ns

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 62mH, I<sub>AS</sub> = -2.7A, V<sub>DD</sub> = -50V, R<sub>G</sub> = 25 Ω, Starting T<sub>J</sub> = 25°C 3. I<sub>SD</sub>  $\leq$  -3.5A, di/dt  $\leq$  200A/μs, V<sub>DD</sub>  $\leq$  BV<sub>DSS</sub>, Starting T<sub>J</sub> = 25°C 4. Pulse Test : Pulse width  $\leq$  300μs, Duty cycle  $\leq$  2% 5. Essentially independent of operating temperature

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## **Typical Characteristics**

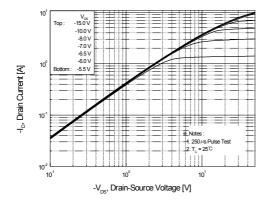


Figure 1. On-Region Characteristics

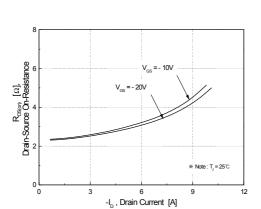


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

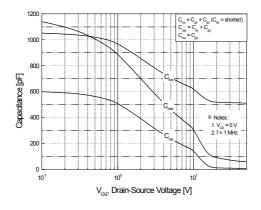


Figure 5. Capacitance Characteristics

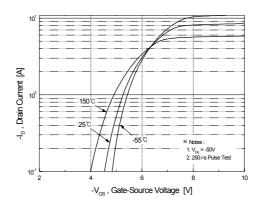


Figure 2. Transfer Characteristics

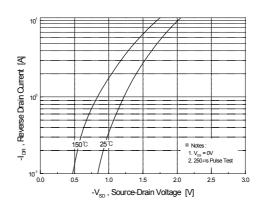


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

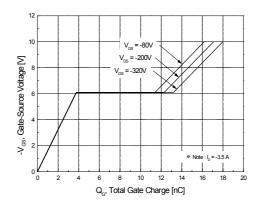
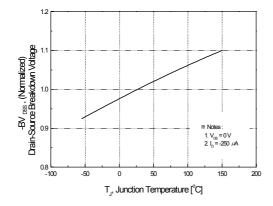


Figure 6. Gate Charge Characteristics

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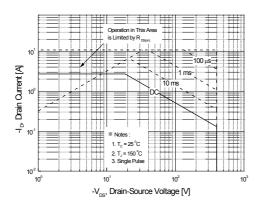
## Typical Characteristics (Continued)



2.5 (Noming 1.5) (

Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



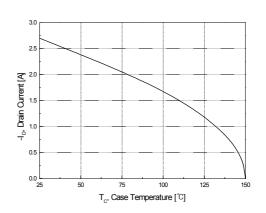


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

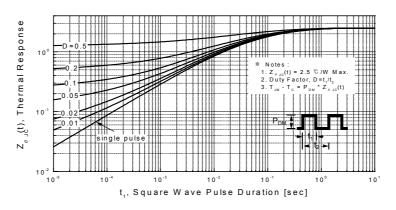
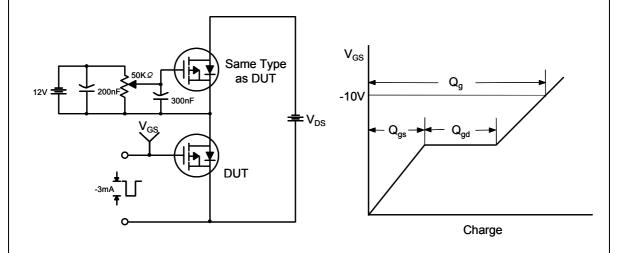


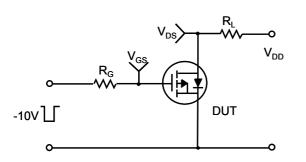
Figure 11. Transient Thermal Response Curve

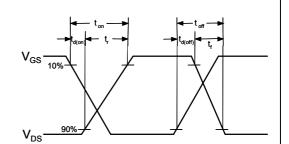
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### **Gate Charge Test Circuit & Waveform**

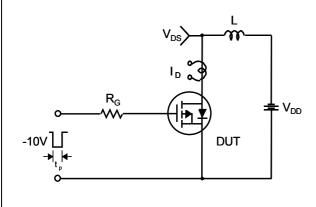


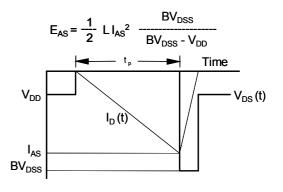
### **Resistive Switching Test Circuit & Waveforms**



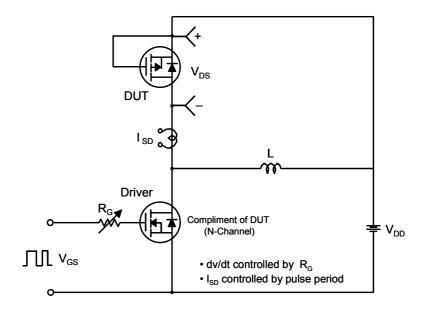


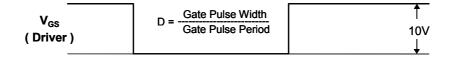
### **Unclamped Inductive Switching Test Circuit & Waveforms**

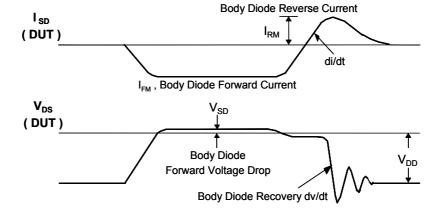




#### Peak Diode Recovery dv/dt Test Circuit & Waveforms



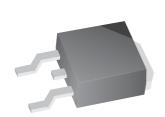


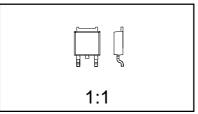


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#### **Mechanical Dimensions**

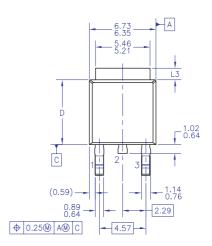
# TO-252 (DPAK) (FS PKG Code 36)

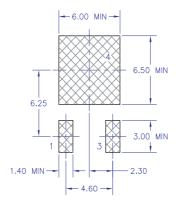




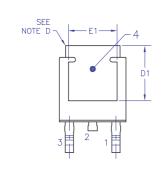
Scale 1:1 on letter size paper Dimensions shown below are in: millimeters

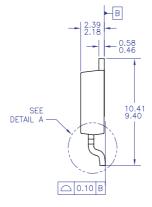
Part Weight per unit (gram): 0.33

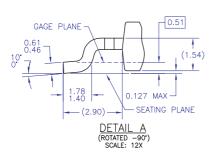




LAND PATTERN RECOMMENDATION







- NOTES: UNLESS OTHERWISE SPECIFIED

  A) ALL DIMENSIONS ARE IN MILLIMETERS.

  B) THIS PACKAGE CONFORMS TO JEDEC, TO-252, ISSUE C, VARIATION AA & AB, DATED NOV. 1999.

  C) DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.

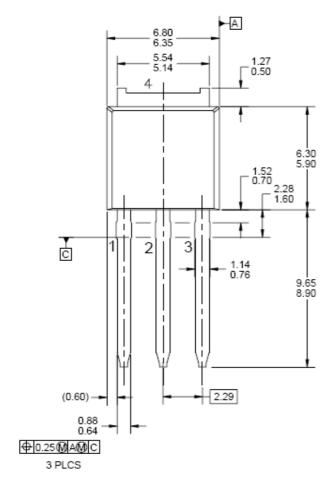
  D) HEAT SINK TOP EDGE COULD BE IN CHAMFERED CORNERS OR EDGE PROTRUSION.

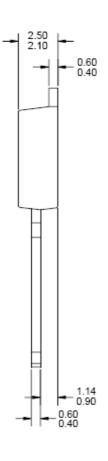
  E) DIMENSIONS L3,D,E1&D1 TABLE:

	OPTION AA	OPTION AB
L3	0.89-1.27	1.52-2.03
D	5.97-6.22	5.33-5.59
E1	4.32 MIN	3.81 MIN
D1	5.21 MIN	4.57 MIN

## **Mechanical Dimensions**

## I - PAK







Dimensions in Millimeters





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No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.
Obsolete	Not In Production	Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.

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